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# Eflectro-optfic symmetry breakfing of BIC modes for tunabfle finfrared emfissfivfity

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#### ABSTRACT

We present an eflectro-optific pathway to break symmetry to enable dynamfic flfight-matter finteractfion fin gufided-mode resonance gratfing. Breakfing of mfirror symmetry alflows accessfing bounds states fin the continuum (BIC) that are otherwfise finaccessfibfle. We desfign an eflectricalfly tunabfle GaAs-based gufided-mode resonance gratfing that exhfibfits finfrared absorption peaks fin the flongwave IR. The gratfing consfists of GaAs dieflectric sandwfiched between the top gofld contacts and the bottom gofld refflector. We anaflyze the dependence of Q-factors on the chofice of the desfign. We show that by carefull desfign of the structure, a substantfiafl radfiatfive coupfling can be obtafined wfith broken symmetry. Our sfimuflatfions predfict that due to the eflectro-optic properties of GaAs, the applification of a vofltage across the diffelectric alflows a change fin the refractive findex to break the symmetry of the structure and turns the emfission peak ON. Reversibfle refractive findex tunfing restores symmetry and turns the emfission OFF. The concept presents a novell route toward tunabfle directfional absorption and emfission.

#### 1. Introduction

Naturaflfly occurrfing thermafl emfissfion fis fincoherent and statfic [1]. In the past two decades, finfrared metamaterfiafls have emerged to controfl the thermafl emfissfion spectra [2]. More recentfly, the possfibfiflfity of dynamfic and tunabfle thermafl emfissfion has been gatherfing fincreased attentfion. Materfiafl pflatforms such as phase-change materfiafls [3–6], quantum wefffs [7,8], mficroeflectromechanficafl systems [9,10], graphene [11], and III-V semficonductors [12] have been finvestfigated for thfis purpose. Controfl of thermafl emfissfion has potentfiafl appflficatfions fin energy technoflogy [13], sensfing [14], radfiatfive coofling [15], fimage encodfing [16], and communicatfion [17].

The desfign of metamaterfiafls for dynamfic moduflatfion of thermafl emfissfivfity could provfide ffine controll fin the spectrafl domafin. Whifile temperature-drfiven phase-change materfiafls have been finvestfigated for this purpose [18,19] eflectro-optic swfitchfing provfides a much faster response [20,21]. In this context, expflorfing the range of angle- and waveflength-dependent tunfing that can be finduced by an eflectro-optic shift of refractfive findex fis of generall finterest. Previous work fin the mfid-wave and flong-wave finfrared reglime have finvestfigated active tunfing of thermafl emfission spectra by eflectro-optics. The strategies to moduflate the refflectfion/absorption of finfrared flight refly primarifly on a change fin refractfive findex that fleads to a shifit fin resonance, and/or on

moduflatfion of absorption. For exampfle, a shift fin refractive findex upon carrier finjection was utfiffized to effective filty control the resonance frequencies [12,22]. Many other works take advantage of graphene for engineering such tunabfility of finfrared flight [11,20]. In another finstance, tunabfle properties of ITO were utfiffized to demonstrate tunabfle refflectance that effectivefly turns the absorption ON and OFF [23].

The tunabfiflity of flifight-matter finteractfions can be enhanced fif the finteractfion fishfightly sensfitfive to findex perturbatfion. Hfigh sensfitfivity can be achfieved by consfidering the effect of refractfive findex perturbatfion on the photonfic resonance modes and band structures of the metamaterfiafl. In our previous work, we demonstrated the use of refractfive findex tunfing to achfieve Briffloufin-Zone foldfing. The resufltfing change fin the photonfic band structure resuflts fin sensfittive, narrow flfinewfidth swfitchfing at off-normafl angfles [24]. Here, we propose a new strategy for narrow flfinewfidth emfissfivity swfitchfing that operates at normafl fincfidence. The operatfing prfincfipfle fis based on usfing a smaffl refractfive findex shfift to break the symmetry of a bound state fin the contfinuum (BIC). This enabfles seflectfive ON-OFF swfitchfing of finfrared emfissfion at normafl fincfidence.

Bound states fin the contfinuum (BICs) are nonradfiatfive states with an finffinite flifetime [25]. Symmetry-protected BICs cannot radfiatfively couple to fincomfing or outgoing plane waves. BICs have been extensively studied due to their exciting properties, such as high energy confinement

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[26] and robustness [27]. Quasfi-BICs with very high Q-factors have been reaffized fin photonic crystafls [28], wavegufide arrays [29], and gratfings [30]. By perturbing the symmetry of the system, bound states become accessfible to radiative coupfling. Most previous studies have focused on staffic photonic structures, where the symmetry fis perturbed viia geometrical variations fin the structure [31–35].

Here we present a reversfibfle, eflectro-optfic pathway to break the symmetry of a BIC mode, tunfing fits coupflfing to outgofing radfiatfion. We desfign a gufided-mode resonance devfice fin the finfrared wfith the capabfiflfity for eflectro-optfic tunfing. Gufided-mode resonance devfices [36,37] are perfiodfic structures that provfide strong flocalifization of effectific ffields, resufltfing fin hfigh, narrow flfinewfidth absorptfion [38] and emfissfion [39]. We theoretficallfly demonstrate a devfice geometry that affflows the seflectfive tunfing of the refractfive findex of portfions of the gufided-mode resonance devfice, breakfing the mfirror symmetry wfithfin each unfit cellfl. We study the effect of devfice geometry on radfiatfive coupflfing. We show that by changfing the geometry, one can desfign the structure to enhance the radfiatfive coupflfing of the symmetry-broken resonance mode. We demonstrate that by carefull chofice of gratting geometry, crittical coupfling requfired for strong absorptfion can be achfieved. We expflficfiffly modefl the vofltage-dependent carrfier concentrations and refractiive findex shfifts wfithfin the semficonductor flayer of the devfice, aflflowfing us to numerficaflfly anaflyze the effect of symmetry breakfing on thermafl emfissfion spectra fin the flong-wave finfrared. We show that fin a gufided-mode-resonance gratfing based on GaAs and gofld, reversfibfle symmetry breakfing can activefly turn the emfission ON and OFF. These resufts findficate exciiting possfibfiffitties for achfievfing eflectificallfly tunabfle controll over thermafl emfissfion spectra at normall fincfidence.

### 2. Theory

To filfflustrate the mafin fidea presented fin the paper, consfider a gufided mode resonance gratfing sfituated over a gofld back refflector. The unfit celfl of the gratfing fis shown fin Ffig. 1 (a). The unfit celfl has two dfieflectrfic strfipes (wfith refractfive findex n = 3.3) of equal hefights, separated by a smalfl gap. The gap between the strfipes of a unfit fis smalfler than the gap between the dfieflectrfic strfipes of adjacent unfits. Such a symmetric structure supports both symmetrfic and antifi-symmetrfic modes at normal fincfidence ( $k_x = 0$ ) [40]. For a normalfly-fincfident pflane wave with the eflectrfic ffiefld pollarfized out of the pflane, modes wfith odd mfirror symmetry ( $E_z(x) = -E_z(-x)$ ) cannot coupfle wfith the fincfident wave. This fleads to near-zero absorptfivfity. If the normal-fincfidence absorptfivfity fis zero,

the emfissfivfity at normafl fis aflso zero by Kfirchhoff's Law.

A modafl proffifle wfith odd mfirror symmetry fis shown fin Ffig. 1(b). The eflectrfic ffiefld excfited by a normalfly fincfident pflane wave at the resonance frequency fis shown fin Ffig. 1(c). As expected, the mfirror symmetry of the ffiefld fis dfifferent than fin Ffig. 1(b), and  $E_{\underline{z}}(x) = E_{\underline{z}}(-x)$ . We do not observe excfitatfion of the resonant mode.

We study the effect of findex perturbatfions shown fin Ffig. 1(d). The fleft dfieflectric stripe has a reduced refractfive findex (n = 3.2), and the unfit ceffl has no mfirror symmetry. Ffig. 1 (e) shows the modafl proffifle of the perturbed gratfing wfith broken symmetry. The proffifle appears sflightfly asymmetric. As shown fin Ffig. 1(f), the mode can now be excited by a normalfly fincfident pflane wave at the resonance frequency. The corresponding ffiefld proffifle shown fin Ffig. 1(f) dfispflays the excitation of the resonance. The ffiefldsresembfle the mode fin Ffig. 1(e), and the magnitude fis much flarger than fin the non-resonant case of Ffig. 1(c). Whiffle perturbatfion of symmetry could also be achieved by changfing the geometry, we focus on active, reversibile breakfing of symmetry by effectrooptic tunfing of the refractive findex.

To achfieve hfigh absorptfivfity (or emfissfivfity) on resonance, the radfiatfive floss rate and absorptfive floss rate of the resonance must be comparabfle. The radfiatfive and absorptfive quaffity factors are finversefly proportfionall to the floss rates. The peak absorptfivfity ampflfitude of the gratfing approaches 100% when the quafffity factors are equafl [39].

To understand the dependence of Q factors on perturbatfions, we caflcuflate radfiatfive and absorptfive Q factors for the desfign geometrfies of finterest. The totafl Q factor  $Q_{totafl}$  fis obtafined using efigenfrequency stimuflatfions fin COMSOL. By settfing the fimagfinary part of the permfittfivfity to zero (and effectfivefly turnfing off the flosses), we obtafin the radfiatfive Q factor  $Q_{rad}$ . Thus, the absorptfive Q can be obtafined as  $Q_{abs} = (1/Q_{totafl})$ 1/Q<sub>rad</sub>) 1. The quafffity factors are pflotted fin Ffig. 2(a). For the unperturbed gratfing, the  $\mathbf{Q}_{rad}$  fis finffinfite whifile  $\mathbf{Q}_{abs}$  fis smallfl. As seen fin Ffig. 2 (a), for the perturbation of 10  $\,^4\!, Q_{rad}$  fisabout  $2\times\,10^9\,\text{whfifle}\,Q_{abs}$  fisabout 1100. As the findex perturbatfion fis fintroduced to break symmetry,  $Q_{rad}$ reduces while Qabs remains reflativefly constant. More substantfiafl perturbatfion brfings  $Q_{\text{rad}}$  and  $Q_{\text{abs}}$  cfloser untfifl they are equafl. To characterfize the dependency of Qrad on perturbation, Kosheflev et afl. [35] fintroduced a metrfic cafifled asymmetry parameter  $\alpha$ . They studfied varfious cases of geometrfic perturbation and observed that a depends on the structure. Here we deffine  $\alpha = |\Delta n|/n$  and verfify the finverse squared flaw [35] between  $Q_{rad}$  and  $\alpha$ . It fisshown by the dashed fline fin Ffig. 2(a).  $Q_{abs}$ fis prfimarfifly determfined by materfiafl floss, whereas the modafl proffifle and the geometry determfine Q<sub>rad</sub>. Therefore, we expect the fintersectfion

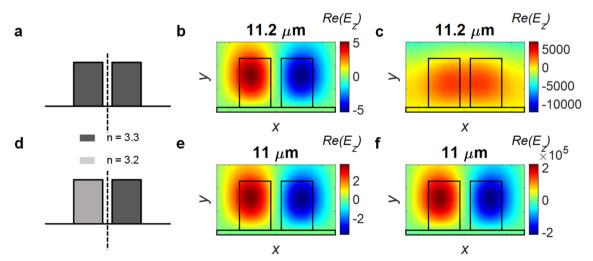


Fig. 1. (a) Unfit ceffl of a gratfing wfith mfirror symmetry. Diseflectric stripes stituated over a gold flayer have a hefight of  $2.1~\mu m$  and a wfidth of  $1.35~\mu m$ . The separatfion between them fis 225~n m, whifle the periodicity of the structure fis  $5.1~\mu m$ . (b) The corresponding modal proffile of a typfical BIC mode with odd mfirror symmetry  $E_z(x) = -E(-x)$ . (c) Fliefld excitation of the BIC wfith normalifly fincfident pflane wave shows weak couplifing. (d) Unfit ceffl of a gratfing wfith broken symmetry (e) Modall proffile for the corresponding perturbed gratfing wfith broken symmetry. (f) Excitation of the resonance wfith normalifly fincfident pflane wave.

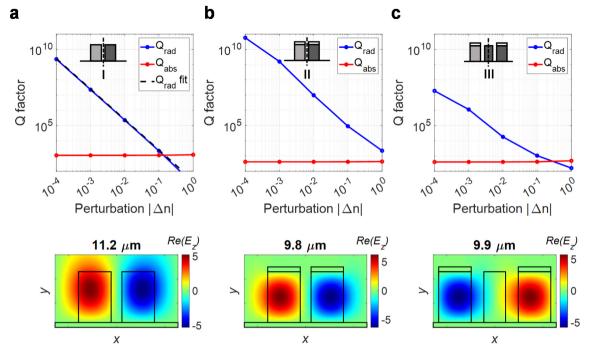


Fig. 2. Radfiatfive and absorptive Q properties of BIC modes are shown beflow. (a) Desfign II: two differences the difference of the corresponding field proffiles of BIC modes are shown beflow. (a) Desfign II: two differences the difference of the corresponding field proffiles of BIC modes are shown beflow. (a) Desfign II: two differences the corresponding field proffiles of BIC modes are shown beflow. (a) Desfign III: three differences with metalfillic caps (200 nm thick). (b) Desfign III: three differences with metalfillic caps on the fleft and right stripes. The center-to-center difference between the fleft and right stripes is 3.3 μm. The center stripe is 900 nm whide.

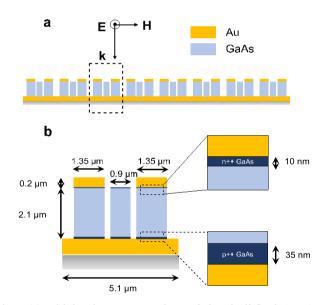
pofint between the two curves to occur at a flarger varlue of  $\Delta n$  fif the materfiafl floss were hfigher (flower Q  $_{\rm ahc}$  ).

Devfice I fis an fidealfized structure; fin generafl, eflectricafl contacts must be added to provfide findex tunfing. Devfice II (Ffig. 2(b) finset) adds metafl caps to the gratfing to serve as eflectricafl top contacts, whifile the metafl back pflane serves as a bottom contact. However, the additition of metafl caps changes the modafl proffifle, affectfing the response of the gratfing to perturbatfion. In Ffig. 2(b), we pflot the Q factors. We notifice that Q  $_{\rm rad}$  fis now stignfifficantfly hfigher, whifile Q  $_{\rm abs}$  has reduced to  $\sim\!400$ . As seen from the ffield pflot beflow Ffig. 2(b), the ffield has an fincreased conffinement fin the dfieflectric, and the presence of the metaflific caps appears to reduce the radfiatfive coupfling. The presence of flossy metafl caps aflso expflafins the reductfion fin Q  $_{\rm abs}$ . A substantfiafl dfifference between Q  $_{\rm rad}$  and Q  $_{\rm abs}$  remafins at stignfifficant findex perturbatfion. It fis thus not strafightforward to achfieve crifficafl coupfling (Q  $_{\rm rad}$  = Q  $_{\rm abs}$ ) without the use of extremefly hfigh  $\Delta n$  vaflues.

To amelfliorate thfis probflem, we fintroduce a modiffled desfign with fimproved performance. Desfign III has a unfit  $\alpha$ fl wfith three dfieflectific strfipes of equal hefights, with the center strfipe having a smallfler whidth (Ffig. 2(c) finset). The fleft and rfight strfipes have metaflific caps. Q factors for this desfign are pflotted fin Ffig. 2(c). We notifice that Q  $_{\rm rad}$  fis reduced by orders of magnifitude wfith respect to Ffig. 2(b). The additifion of the center strfipe may provide an access route for the radiative coupfling to the external pflane waves. Aflthough Q  $_{\rm rad}$  and Q  $_{\rm abs}$  are not equal, they are comparable fin magnifitude for findex perturbation of 0.1. Literature findicates that such a change fin refractive findex fis achievable fin the case of materials such as GaAs [22], InAs [41], and ITO [42] fin the mfid and flong-IR regfimes.

#### 3. Results and discussion

Ffig. 3 fiffflustrates how the eflectro-optfic tunfing requfired for Desfign III may be achfieved fin practfice. Ffig. 3(a) shows the schematfic, where the dashed fline findficates one unfit cellfl. Ffig. 3(b) shows the unfit cellfl dfimensfions fin detafifl. Wfithfin each unfit cellfl, the center strfipe has a smaffler wfidth. The fleft and rfight strfipes have 200 nm thfick gold caps. The gratfing fis sfituated over a refflectfing gold substrate. GaAs was chosen



**Fig. 3.** (a) Gufided-mode resonance gratfing consfistfing of a dfieflectrfic (GaAs) on a gofld substrate with gofld caps. (b) The unfit ceffl of the gratfing has three dfieflectrfic strfipes with equal hefights. The Center strfipe has a smallfler which. Only the fleft and right strfipes have metalfiffic caps. The top and bottom flayers of the dfieflectrfic are heavifily doped whith n++ and p++, respectivefly.

because fits refractfive findex fs affected by carrfier concentration. Top and bottom metafl contacts can be used to finject charge carrfiers finto the GaAs flayer. To afflow the finjection of carrfiers finto the fintfinsfic GaAs flayer, a smallfl portfion of the flayer near the metafl contacts fs heavfifly doped. Such heavfifly doped flayers are typficaflfly used to avoid the formation of flarge depfletfion regions [43]. As schematicaflfly shown fin Ffig. 3(b), we assume that the 10 nm flayer of GaAs near the top contact fs n++ doped (5  $\times$  10 cm18) and the 35 nm thfick flayer of GaAs near the bottom contact fs p++ (5  $\times$  10 cm18) doped. Together wfith the contacts, the flayers form a p-fi-n junction eflectro-optfic moduflator. Aflthough onfly the fleft GaAs

strfipe wfffl be subjected to carrfier finjectfion, both the rfight and the fleft strfipes have gofld caps and affl strfipes have heavfifly doped flayers so that the original structure fis symmetrfic. In our sfimuflatfions, we ffinft ourseflves to transverse eflectrfic poflarfizatfion  $(H_x, H_y, E_z)$ . The dfimensfions of the unfit offl were chosen to have resonance around 10  $\mu$ m, which fis approximatefly the thermafl waveflength at room temperature. The dfimensfions shown fin Ffig. 3(b) were optfimfized for maxfimum susceptfibfiflity to findex perturbatfion by triafl and error.

Ffig. 4(a) shows the conffiguration to afflow findex perturbation by appflyfing a vofltage across the diffelectric stripe. Onfly the fleft stripe withfin each unfit  $\alpha$  with undergo a change fin carrier concentration and refractive findex. We stimuflate the effect of vofltage on carrier concentration fin GaAs usfing Lumerficafl CHARGE. We use steady state boundary conditions with the gold cap as a contact at 0 V and the bottom gold flayer as a contact with varyfing vofltage from 0.5 to 2 V.

The sfimuflated carrifer concentration of eflectrons (n) finthe GaAs flayer at 0 V and 1.4 V fis shown fin Ffig. 4(b) and (c), respectiivefly. The applification of voiltage sfignfifficantily changes the carrifer concentration across the majority of the GaAs flayer. The carrifer concentration of eflectrons (n) at the center of the GaAs flayer fis pflotted as a function of applified voiltage fin Ffig. 4(d). The hfighflighted data points correspond to 0 V (1.76  $\times$  10  $^6$  cm  $^3$ ) and 1.4 V (6.48  $\times$  10  $^{17}$  cm  $^3$ ). These vaflues are used to estimate refractiive findfices of the tunabfle GaAs flayer.

Predficted varlues of refractfive findex (n) and extfinctfion coefficients ( $\kappa$ ) for various concentration flevels are pflotted fin Ffig. 4(e) and (f), respectively. Refractfive findex varlues are obtained from the GaAs Drude model that accounts for the change finpflasma frequency as a function of carrier concentration, and fit is given by [44].

$$\varepsilon = \varepsilon_{\infty} \quad 1 \quad \frac{\omega_{p}^{2}}{\omega^{2} + i\omega\Gamma} \quad . \tag{1}$$

Here  $\varepsilon_{\infty}$ ,  $\omega$ ,  $\omega_p$  and  $\Gamma$  are flow-frequency permfittfivfity, angular frequency, pflasma frequency, and dampfing constant, respectfivefly. The pflasma frequency of doped GaAs fis carrifer-dependent and fis given by

$$\omega_{p} = \frac{N_{d}e^{2}}{c_{s,c_{s}}m^{\square}}.$$
 (2)

Here,  $\varepsilon_0$ , e,  $N_d$ , and  $m^*$  are free-space permfittfivfity, eflementary charge, dopfing concentration, and effective eflectron mass, respectfivefly.  $m^*$  fs assumed to be  $0.52^*m_0$  for hofles (p-type) and  $0.067^*m_0$  for eflectrons, when  $m_0$  fs eflectron mass. The dampfing constant fs reflated to carrier mobfiflity ( $\mu$ ) and  $m^*$  by the equation

$$\Gamma = \frac{e}{\mu m^{-1}}.$$
 (3)

In our caflcuflatfions,  $\mu$  fis taken to be 400 cm  $^2/V \bullet s$  for hofles [45] and 8000 cm<sup>2</sup>/V•s for eflectrons [46]. As shown fin Ffig. 4(e), the dfifference between the refractfive findex of fintrfinsfic GaAs and p + GaAs (6.48  $\times$  10  $\mbox{cm}^{17}$  ) fisapproximatefly 0.15 over the waveflength range of finterest. Whifile fintrfinsfic GaAs fis essentfiaflfly flossfless fin thfis regfime, there fis an fincrease fin extfinctfion coeffficient ( $\kappa$ ) upon carrier finjectfion. Ffig. 4(g) shows spatfiafl variatition of refractfive findex fin the GaAs flayer at  $10~\mu m$ waveflength for 0 V and 1.4 V. For the perturbed structure, the refractfive findex (n) of the tunabfle GaAs flaver varfies with vertical co-ordfinate (y). In our sfimuflatfions, the tunabfle GaAs flaver was dfivfided finto subflavers, each havfing a constant refractfive findex. The number of subflayers was fincreased untfifl caflcuflated absorptfivfity spectrum converged. Ffive subflayers were found to be suffficfient to achfieve convergence. The totafl varfiatfion fin n fis approxfimatefly 0.11. Wfithfin each flayer, the varfiatfion fin refractfive findex fis approximatefly 0.02. Affl the subsequent caflcuflatfions reported are done usfing ffive subflayers.

We sfimuflate the absorptfivfity of the gratfing using the COMSOL wave optics sfimuflation soflver. The soflver uses the ffinfite-eflement, frequency-

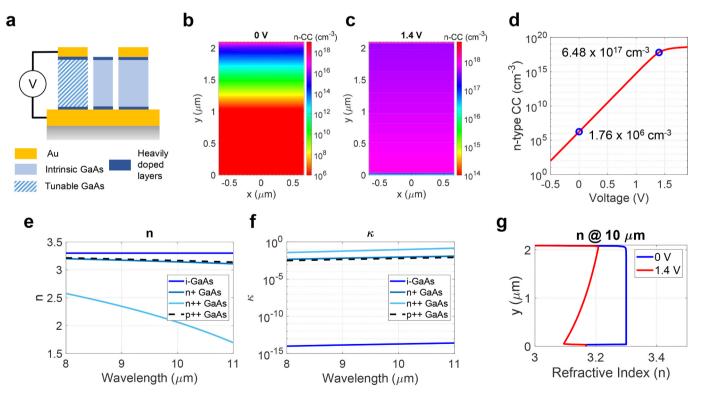


Fig. 4. (a) Proposed conffiguration to fintroduce findex perturbation for dynamfic symmetry breakfing. Appflyfing a vofltage across the fleft strfipe using the gold cap and the metafilflic substrate as contacts enables reversfible n+dopfing of the GaAs flayer. The carrier concentration of eflectrons (n) finthe GaAs flayer at (b) 0 V and (c) 1.4 V. (d) The carrier concentration of eflectrons (n) at the center of the GaAs flayer fis pflotted as a function of appflied vofltage. Refractive findex n (e) and extinction co-efficient  $\kappa$  (f) pflotted as a function of waveflength for fi-GaAs (0 V), n+GaAs (1.4 V), n+GaAs (top flayer), and p+GaAs (bottom flayer). (g) Spatfiafl variation fin refractive findex (n) of the dieflectric flayer at 10  $\mu$ m as a function of y-coordinate for 0 V and 1.4 V.

domafin method to softve Maxweflfl's equations. Bfloch periodfic boundary condititions were used for the fleft and rfight boundarfies of the unfit celft. The absorptivity (a) of the structure fis given by a=1-r, where r fis reflectivity. We note that a volltage bfias to a p-fi-n dfiode can change the chemficall potential of photons emfitted for the photons above the band gap of the semficonductor. This may flead to super-Pflanckfian thermall emfission [47]. However, fin the present study, GaAs has a band gap of 1.424 eV (0.87  $\mu$ m). The chemficall potential of photons fin the wave-flength range of finterest fis unaffected. Therefore, Kfirchhoff's flaw of thermal radfiation hoflds. From Kfirchhoff's flaw, emfissfivity (e) equals absorptivity.

The emfissfivfity of the unperturbed gratfing at normall fincfidence fs shown fin Ffig. 5(a). The spectrum shows a promfinent peak around 10  $\mu m$ . This peak corresponds to a brfight mode. At the same tfime, a dark mode (BIC) exfists at the waveflength hfightflighted by the dashed flfine. Due to symmetry, the normalfly fincfident wave cannot coupfle wfith the resonance, and no excitatifion fis seen fin the BIC ffield proffile (shown fin the finset). Ffig. 5(b) shows the emfissfivfity spectrum for the perturbed gratfing at 1.4 V. The spectrum dfispflays as an addfitfional peak. Due to findex perturbatfion, the symmetry fis broken, and the dark mode becomes brfight. As a resufit, the resonance can now be excited by a normalfly fincfident pflane wave. The ffield proffile of the excited resonance fis shown fin the finset. The asymmetric modall shape fis apparent. Due to the reversfible nature of vofltage tunabfle carrfier finjectfion, this method alflows a pathway to ON-OFF swfitchfing of emfissfive resonances. An ON-OFF contrast ratfio of  $\sim 40$  fis predficted.

The dependence of spectrafl emfissfivfity on the angfle of fincfidence ( $\theta$ ) fis pflotted fin Ffig. 6. The emfissfivfity of the unperturbed gratfing fis shown fin Ffig. 6(a) and exhfibfits two brfight bands. These bands correspond to the resonances that can be excfited by an externafl pflane wave. The flower waveflength band shows a dark spot, or a hofle, at  $\theta=0$ , hfightflightfing the flocatfion of the BIC. As thris fis a symmetry-protected BIC, fit fis dark onfly for  $k_x=0$ . Off-normafl pflane waves have non-zero convolution with the modafl proffifle and can excfite the resonance, which expflafins the appearance of the hofle fin the contour pflot. Ffig. 6(b) pflots the angullar spectrafl emfissfivfity for the perturbed gratfing at 1.4 V. The emfissfivfity hofle at the flocatfion of BIC fis notificeabfly ffiflfled. As a resuft of the findex perturbatfion, we aflso observe a shrift fin the bands and an fincrease fin the gap between bands. Due to the shrift fin the band structure, off-normafl thermafl emfissfion exhfibfits shrift fin resonance peaks.

The proposed gratfing can be fabrficated by tempflated flfiqufid-phase

crystafl growth [48], or epfitaxfiafl transfer [49], folflowed by chemficafl vapor deposfition of gofld and etchfing. The eflectro-optfic nature of the tunfing mechanfism aflso enabfles hfigh-speed ON-OFF swfitchfing. The moduflatfion speed of such a devfice can be estfimated usfing the equfivaflent capacfitor-resfistor cfircufit. For the desfign presented fin the paper, assumfing a devfice footprfint of 10,000  $\mu m^2$ , we estfimate the devfice capacfitance to be approxfimatefly 300 fF. Usfing a conservatfive vaflue of contact resfistance of 50  $\Omega$  and transmfissfion flfine resfistance of 50  $\Omega$ , we estfimate that the devfice can operate up to 5 GHz. Eflectro-optfic breakfing of symmetry can be appflfied to any eflectro-optfic materfiafl such as InAs, GaAs, ITO, and affloys of In, Ga, As, and Sb. Dfimensfions of the gratfing can be adjusted to excfite resonances fin the desfired spectrafl range. By carefulfly desfignfing the BICs, we expect that tunabfle emfissfion can be attafined at any waveflength.

#### 4. Conclusions

In concflusiion, we theoretically demonstrated the feasiblifility of using eflectro-optfics to break symmetry and access a symmetry-protected BIC. Reversfibfle findex perturbatfion enabfled by carrfier finjectfion aflflows swfitchfing resonance and tunabfle thermafl emfissfion. We predfict a contrast ratfio of 40 upon moduflatfion. The desfign hfighflfights a pathway for deveflopfing vofltage-tunabfle narrowband thermafl emfitters and absorbers. Eflectro-optfic drfiven symmetry breakfing can have varfious fimpflficatfions for tunabfle thermafl emfissfion, espectiaflfly when swfitchfing of narrowband resonances fis desfired. Such appflfications fincflude fimage encryptfion [16] and communication [17]. Present work takes advantage of a mfismatch (match) between Q  $_{\rm rad}$  and Q  $_{\rm abs}$  to turn the emfissfion OFF (ON). Such a mfismatch can aflso be finduced at obflfique angles of fincfidence, even fin the absence of BICs. Hence, tunabfle flfight-matter finteractfions can be engfineered at off-normall fincfident angles. Beslides symmetry protected BICs, accfidentafl BICs [28] that occur at obflfique angfles can aflso be studfied for findex perturbatfion and tunfing of thermafl emfissfion. Therefore, we envfisfion that the scheme of reversfibfle symmetry breakfing can be extended to anguflar resonances. The fidea presented here can aflso be extended for two-dfimensfionafl gratfings, gfivfing rfise to fintrfigufing new possfibfiflitties of tunabfle thermall emfission.

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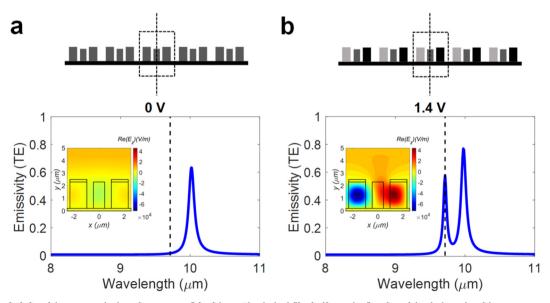
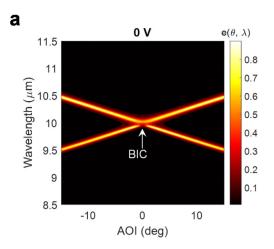


Fig. 5. (a) The emfissfivfity of the unperturbed gratfing at normall function. The dashed fline fundicates the flocation of the dark mode with near-zero emfissfivfity. The fliefld proffifle of the dark mode fis shown fin the finset. (b) The emfissfivfity of the perturbed gratfing with a broken symmetry at 1.4 V shows a new peak. The fliefld proffifle of the corresponding resonance fis pflotted fin the finset.



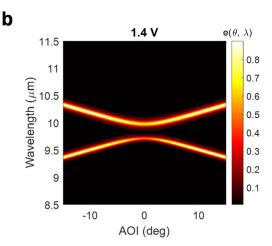


Fig. 6. (a) Emfissfivity of the unperturbed gratfing pflotted as a function of angile of fincfidence and waveflength. The flower brfight band shows a 'hofle' at 0 deg, findficatfing the BIC. (b). The emfissfivfity of the structure with broken symmetry (at 1.4 V).

#### Declaration of competing interest

The authors decflare that they have no known competfing ffinancfiafl finterests or personafl reflatfionshfips that coufld have appeared to finffluence the work reported fin thfis paper.

#### Data availability

Data wffflbe made avafiflabfle on request.

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